

## Notice of References Cited

Application/Control No.

O9/768,500

Examiner

Justin P Misleh

Applicant(s)/Patent Under
Reexamination
TAKAHASHI ET AL.

Art Unit
Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name ,	Classification
	Α	US-6,344,666 B1	02-2002	Yamaguchi et al.	257/98
	В	US-6,201,574 B1	03-2001	Martin, H. Lee	348/315
	С	US-6,278,169 B1	08-2001	Sayuk et al.	257/435
	D	US-5,610,390	03-1997	Miyano, Hitoshi	250/216
	E	US-6,008,511 /	12-1999	Tokumitsu et al.	257/232
	F	US-6,704,051 B1 /	03-2004	Takahashi, Hidekazu	348/315
	G	US-6,093,081 /	07-2000	Nyui et al.	451/6
	Н	US-5,986,704	11-1999	Asai et al.	348/340
	ı	US-6,518,639 B2	02-2003	Ueno et al.	257/432
	J	US-6,137,535	10-2000	Meyers, Mark Marshall	348/340
	к	US-6,069,350	05-2000	Ohtsuka et al.	250/208.1
	L	US-6,339,506 B1	01-2002	Wakelin et al.	359/648
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	a					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.